

EU – Singapore – 1st Joint Researchers Workshop on Semiconductors



Opportunities of Wide Bandgap Devices for Energy Conservation and Emerging Applications

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OUTLINE



- 1. Introduction & Scope
- 2. WBG Fundamentals
- 3. WBG Power Device Status
- 4. Application Demonstrations
- 5. EU Chips JU WBG Pilot Line
- 6. New Areas High Temperature Applications
- 7. Summary & Conclusions



The Societal Challenge

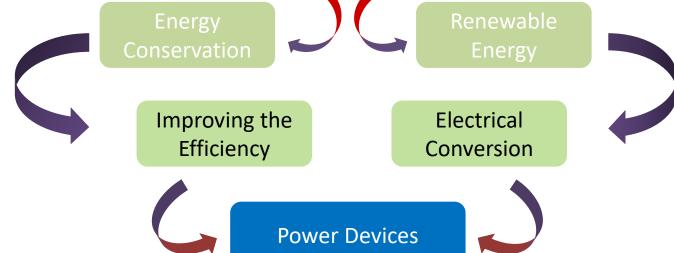






Global Warming/Pollution

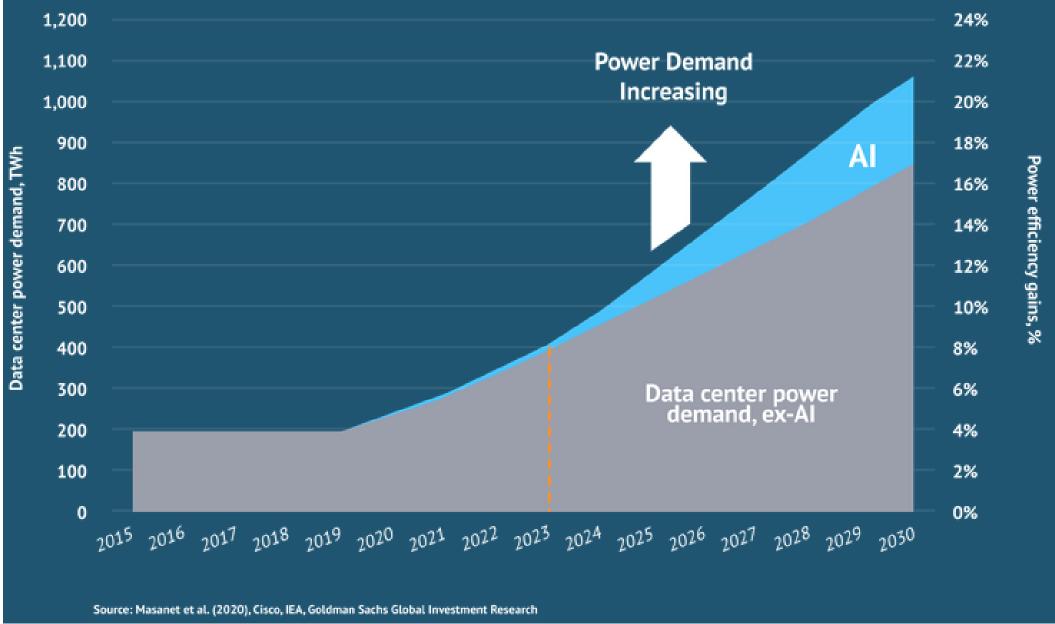






Data Center Power Demand



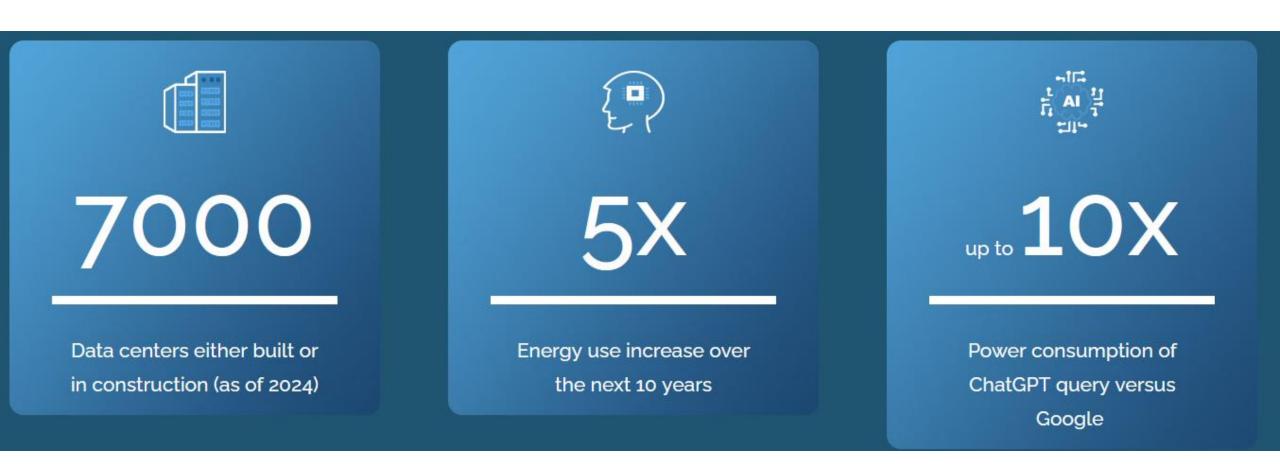




Data center forecast



(source Goldman Sachs, Bloomberg)

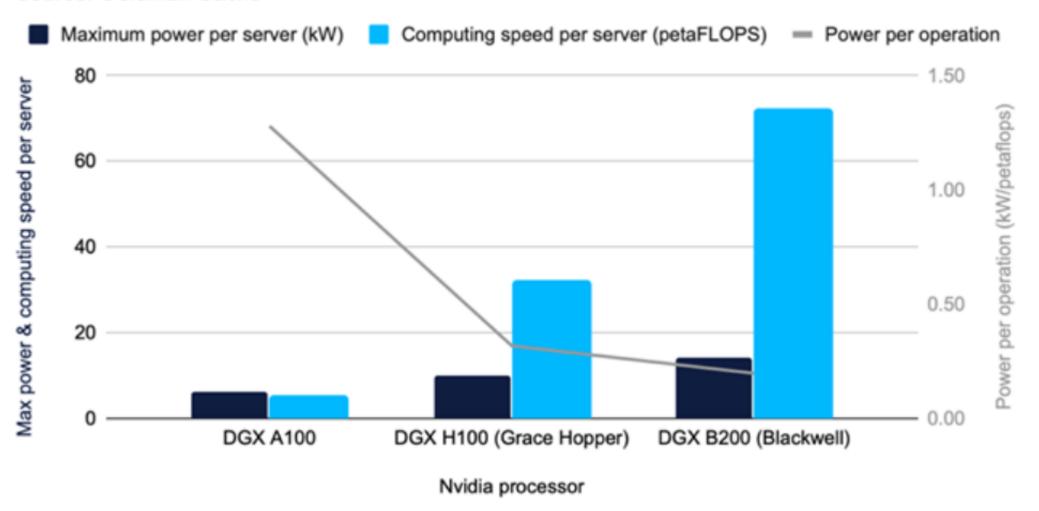






Processors are getting significantly more efficient, but Al's growth still requires ever greater power densities

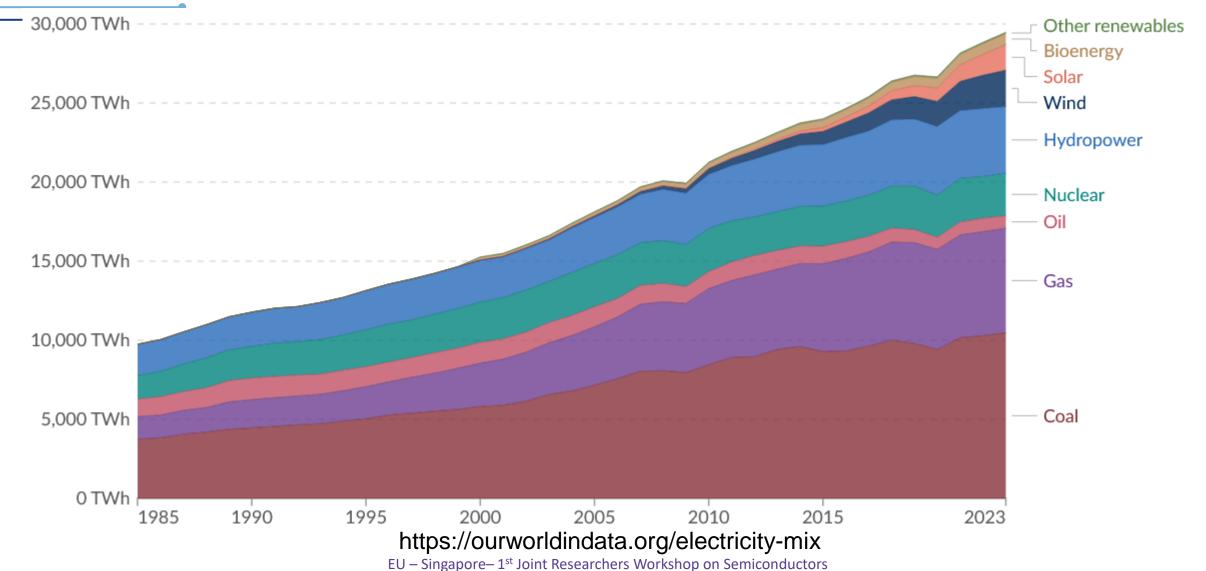
Source: Goldman Sachs





Global Electricity Mix





Mikael Östling, KTH



How about efficiency – What can we expect?



- More than 60% of the generated electrical energy is produced by fossil based fuel
- Urgent to change the energy mix in a sustainable way
- At the same time we need to improve the efficiency in both the way we <u>produce</u> the electrical energy and how efficient we can <u>distribute</u> and <u>consume</u> the energy
- One important technology to improve power electronic efficiency is to introduce
 Wide Bandgap Semiconductors, such as SiC and GaN in our future technology

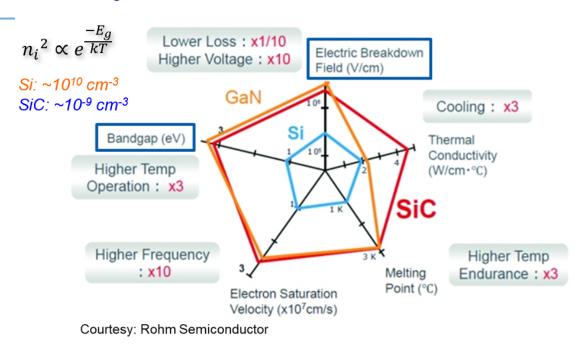
By improving today's power electronics efficiency by only 1% will reduce the consumption by 300 TWh – about 70 typical coal powered plants!





Fundamental WBG Characteristics



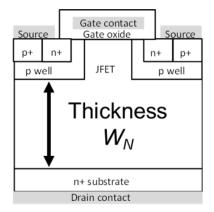


Device Thickness

$$W_{N} = \left(\frac{3}{2}\right) \left(\frac{V_{B}}{E_{C}}\right)$$

Device Resistance

$$R_{ON,SP} = \left(\frac{3}{2}\right)^3 \frac{V_B^2}{\mu_N \varepsilon_S E_C^3}$$



<u>Large Bandgap</u> and <u>Critical Electric Field</u> allow for high voltage devices with thinner layers: lower resistance and associated conduction losses, low leakage, and robust high temperature operation

<u>Thinner layers</u> and <u>lower specific on-resistances</u> allow for smaller form factors that reduce capacitance: higher frequency operation, reduced size passives

Large Thermal Conductivity: high power operation with simplified thermal management

Modified slide from Victor Veliadis, Power America



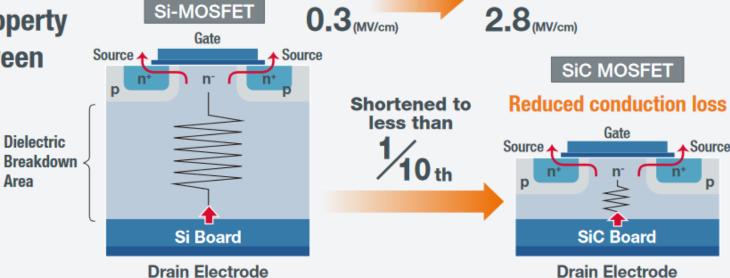


Area





(Dielectric Breakdown **Electric Field Strength)**



Si

High dielectric field breakdown strength provides superior withstand voltage and lower loss



▲Source

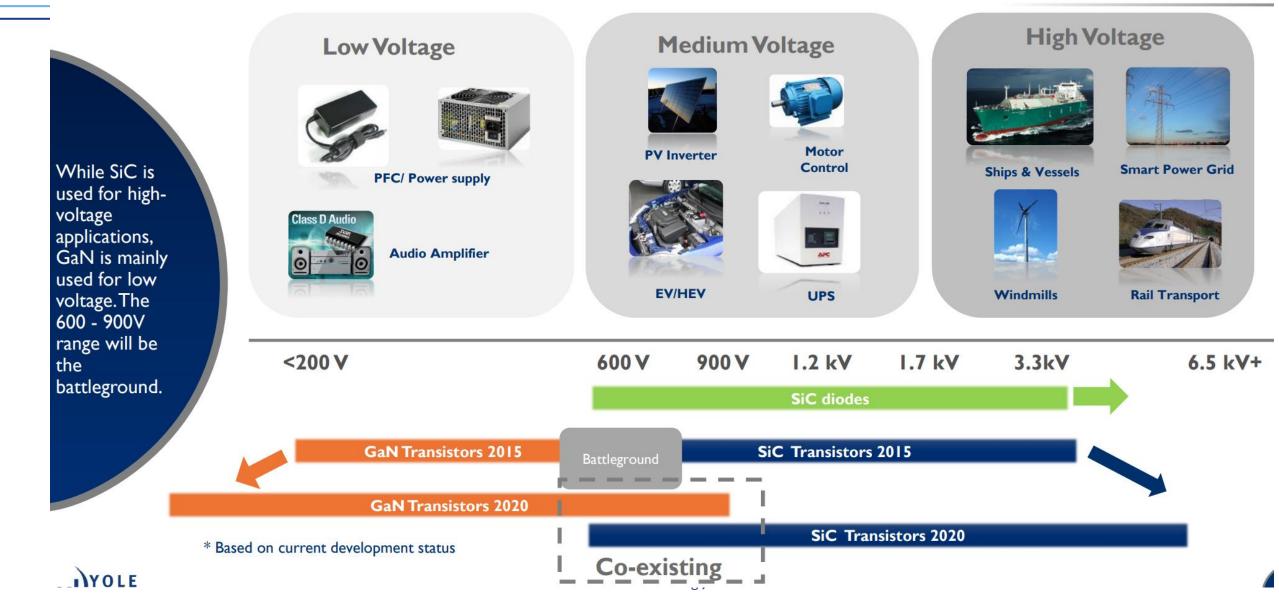
High voltage

Low ON resistance

SiC



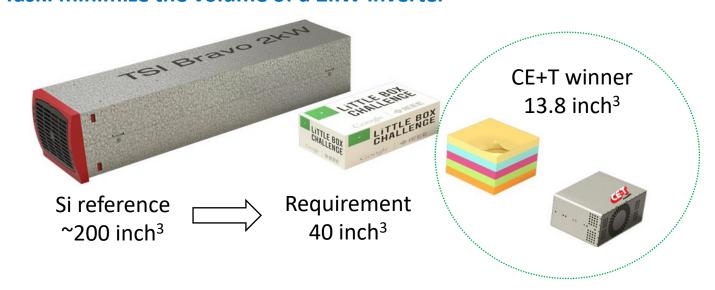






Google little box challenge

Task: minimize the volume of a 2kW inverter





Powered by GaN!

	0	OF T Dames
	Google's request	CE+T Power
Maximum Power Tested	2000VA	2062 VA
olume of the rectangular enclosure	0.655 liter / 40 in ³	0.226 lier / 13.77 in ³
Resulting power density at 2 kW load	3050 W per liter 50W/in ³	8850 W per liter 145.24 W/in ³
DC voltage range	399.5Vdc	300 to 450 Vdc
AC voltage (RMS) output	230or 240 Vac	240 Vac split phase
DC to AC efficiency (CEC Method)	min 95%	95.4%
Voltage total harmonic distortion + noise	1.1%	1.1%
Current total harmonic distortion + noise	1.1%	1.1%

World's First 12 kW PSU for Hyper-Scale Al Data Centers using GaN and SiC



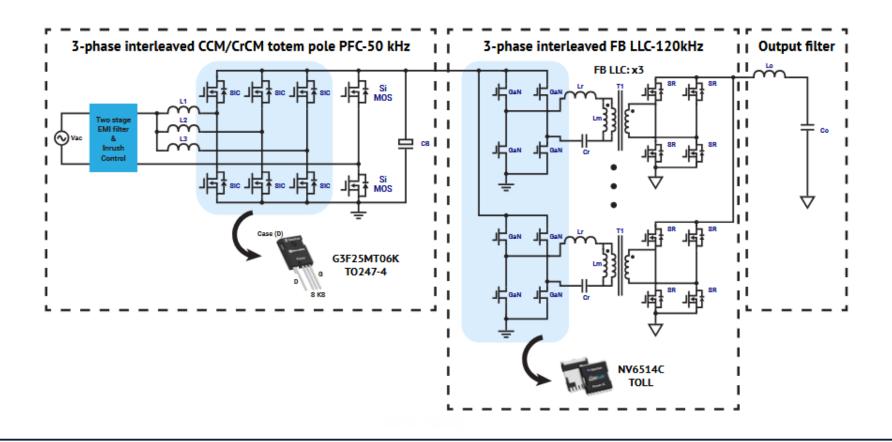




12 x NV6514 TOLL



6 x G3F25MT06K T0247-4



EMI filter, surge protection circuit, etc. to meet safety/regulation requirements

Supports RS485 & CAN communication protocols

Input/Output connector





WBG in Automotive



CONVERTERS & INVERTERS IN EV/H

Where are SiC and GaN?

EV/HEV is a segment where the competition between SiC, GaN, and Si (the incumbent) will be intense

- <u>Technologically</u>
 <u>speaking</u>, SiC is more
 <u>suitable for high-</u>
 <u>power DC/AC</u>
 inverters and GaN is
 <u>better adapted to low-</u>
 <u>power DC/DC and</u>
 AC/DC converters
- However, the choice of SiC or GaN is more complex and depends on numerous criteria, such as technology maturity and device availability
- According to our knowledge, SiC-based diodes have already been implemented in low-power converters for the on-board charger

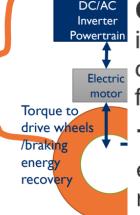
Electric traction motor: Uses power a from the traction battery pack to drive the vehicle's wheels

DC/DC converter: This device converts higher-voltage DC power from the traction battery pack to the lower-voltage DC power needed to run vehicle accessories and recharge the auxiliary battery.

Onboard charger: Takes the incoming AC electricity supplied via the charge port and converts it to DC power for charging the traction battery.

 Traction battery pack: Stores electricity for use by the electric traction motor.

Battery (all-electric auxiliary): In an electric drive vehicle, the auxiliary battery provides electricity to power vehicle accessories.



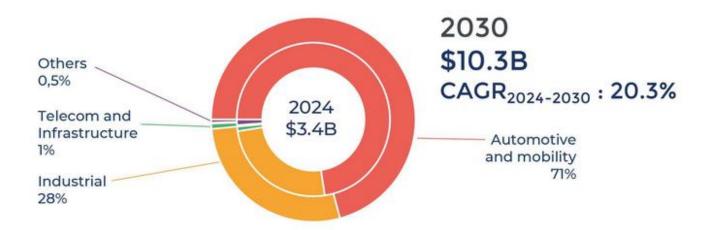




Market Outlook

2024 – 2030 POWER SIC DEVICE MARKET, SPLIT BY APPLICATION

Source: Power SiC 2025 - Markets & Applications report, Yole Group



- · Home appliances
- · PC

Mobile & Consumer



- · EV/HEV
- ·E-motorcycle
- · Train

Automotive and Mobility

- · Data centers
- · Servers
- Base stations
- Telecom and
- Telecom and Infrastructure

- ·UPS
- · Motor drives
- Industrial power supply
- ·DC charging station
- Wind
- Photovoltaics

Industria



- Aerospace applications
- Medical

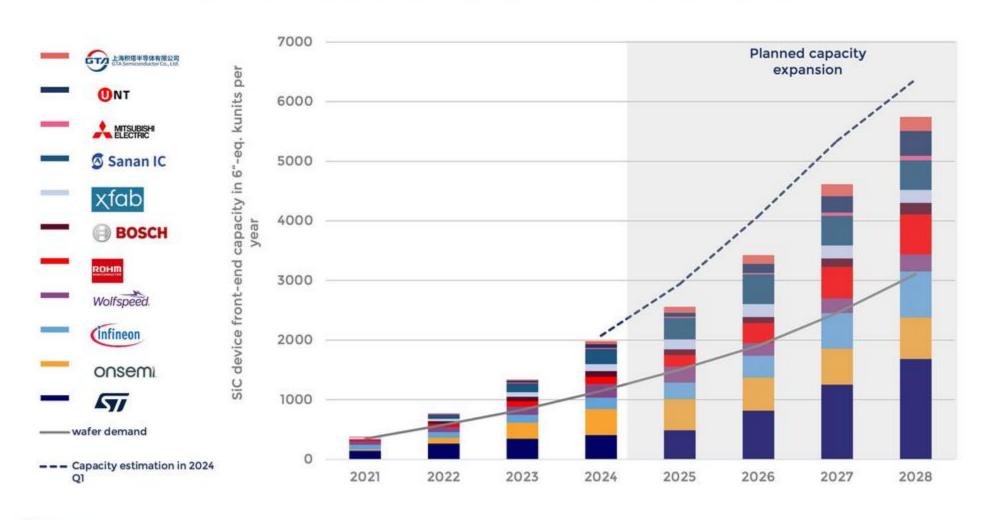
Others





THE LATEST SIC DEVICE CAPACITY FORECAST OF KEY PLAYERS

Source: Power SiC 2025 - Markets & Applications report, Yole Group

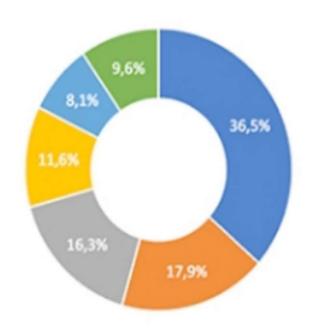






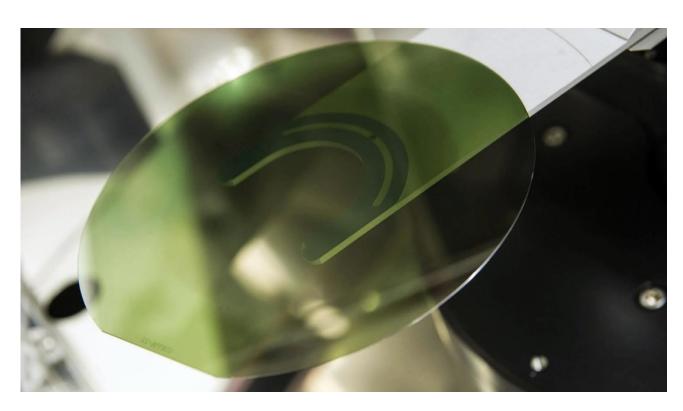
Europe is the market leader

Global market share of suppliers for SiC power devices in 2022 (Market share in terms of sales)

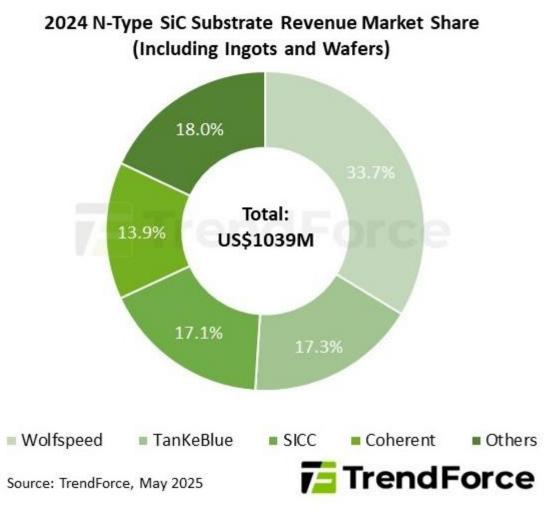


If we add the market share of STMicroelectronics and INFINEON, Europe has more than 50% of the total global market share of SiC power devices.

SiC Wafer Situation

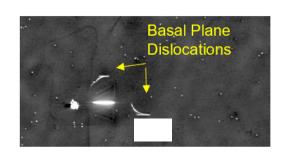


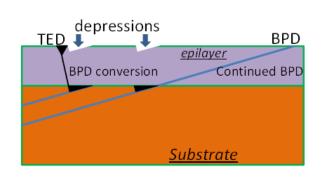
A 200 mm SiC Wafer by STMicrelectronics

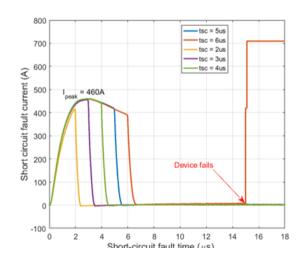


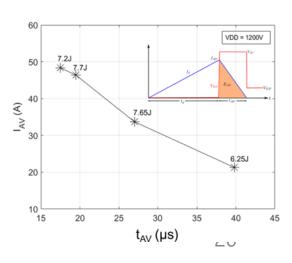
Initial problems with materials quality

- Material and Fabrication optimizations improve device yields and reliability
 - Minimize killer material defects (BPDs, micro-pipes, etc.)
 - Improve wafer planarity
 - Eliminate defect generation during processing (implantation)
 - Reduce Threshold-Voltage-Instability (high quality gate oxide)
- Design rugged SiC devices and fast gate drives for safe operating areas similar to Si
 - Short circuit withstand time similar to that of Si or use fast/intelligent gate drives
 - High Avalanche Energy tolerance



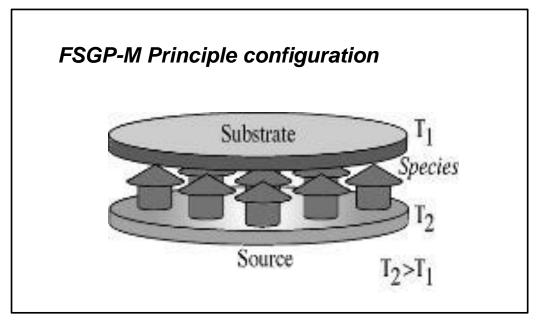






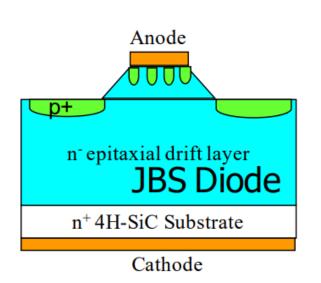
FSGP-M - a flat growth front - the key feature

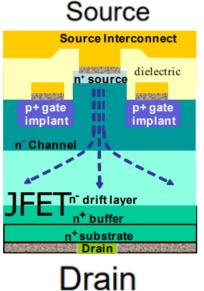
The Fast Sublimation Growth Process – Monocrystalline (FSGP-M), provides perfectly uniform seed and source substrate temperatures and a uniform supply of growth species which ensures that a uniform growth rate is obtained over the whole substrate surface during the entire growth process.

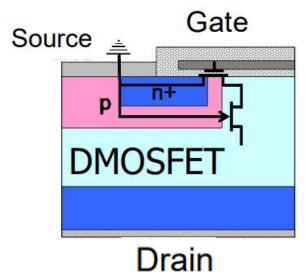


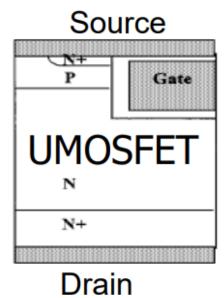
As a consequence, no BPDs are formed either during or post growth. The novel technology enables ultra high crystalline quality over large areas also in thick layers. There is practically no stress inside the crystal and in 6-inch size substrates bow is typically $<5\mu m$ and warp $<15\mu m$. Doping concentration and resistivity are practically constant over the entire substrate surface. We have developed and taken into operation a production system for growth of 6-inch 4H-SiC substrates. Presently a system is being prepared for growth of 8-inch size substrates.

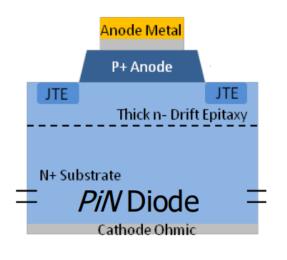
SiC Device Structures

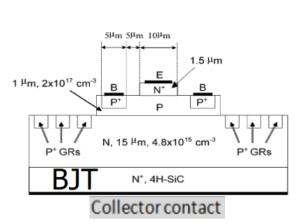


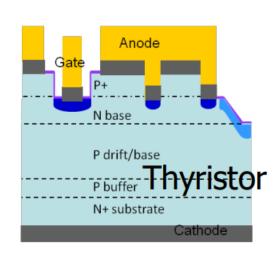


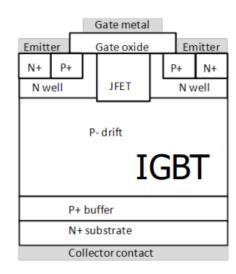






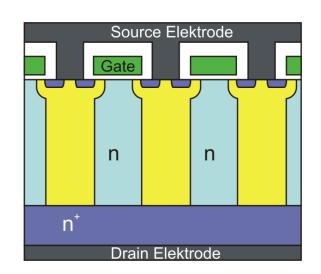


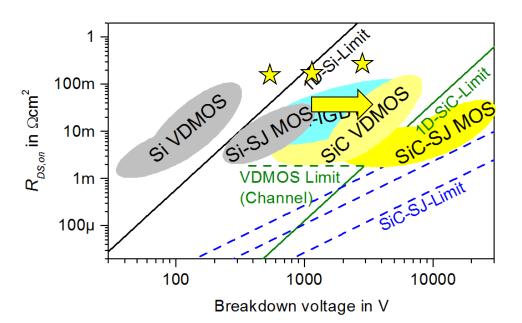




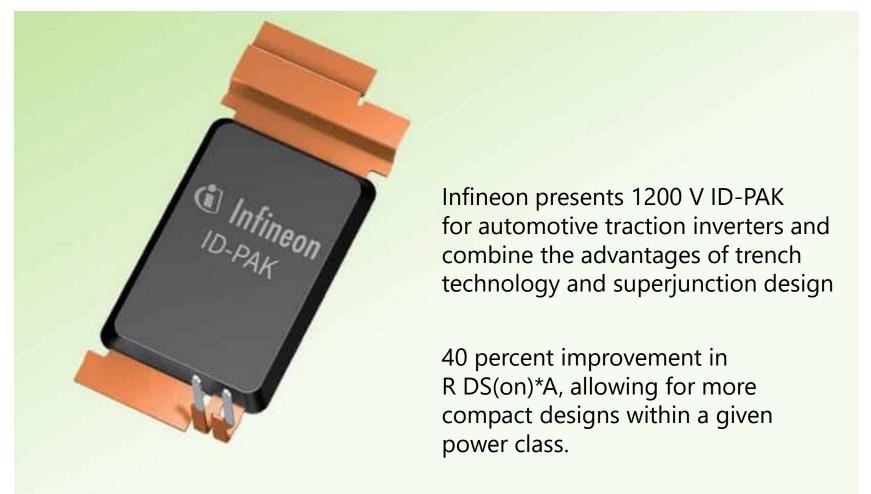
Evolution of Power SiC MOS Technology

- Challenges for further advancements
 - Unipolar high voltage devices
 - Superjunction device topology using vertical pillar structure (approx. 60µm @ 10kV)
 - Concepts (similar to Infineon / Toshiba solutions in Silicon):
 - Mid-energy ion implantation and epitaxial overgrowth (rinse & repeat)
 - High-energy ion implantation (e.g. filter implantation)
 - Deep trench etching and epitaxial refill





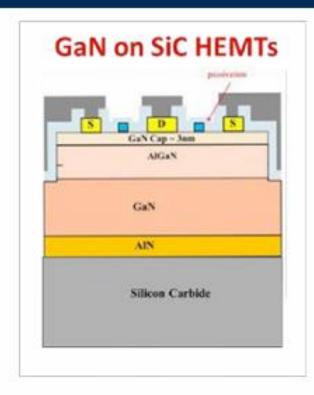
Recent News SiC Trench Superjunction

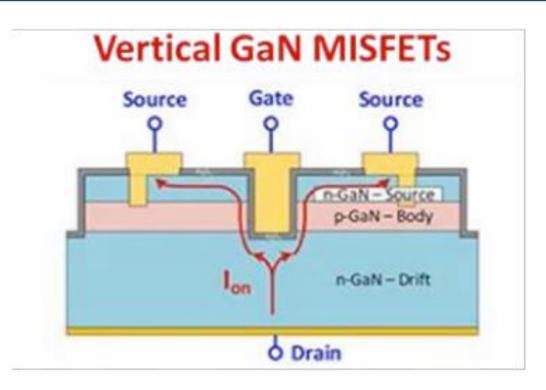


Hyundai Motor Company development teams will engage with Infineon's trench-superjunction technology, leveraging its benefits to enhance their EV offerings



GaN Devices





- Today, all GaN devices are produced on Si or SiC substrates, resulting in horizontal structures with limited scalability and low current capacity.
- Hetero-epitaxy introduces defects that reduce performance and reliability.

The WBG Pilot Line will develop processes for bulk GaN wafers, enabling vertical devices

Lower defect densities; Higher current-carrying capacity; Enhanced scalability and performance





WBG Pilot Line: a major boost for Europe's innovation and competitiveness

Total budget from EU €181,2M

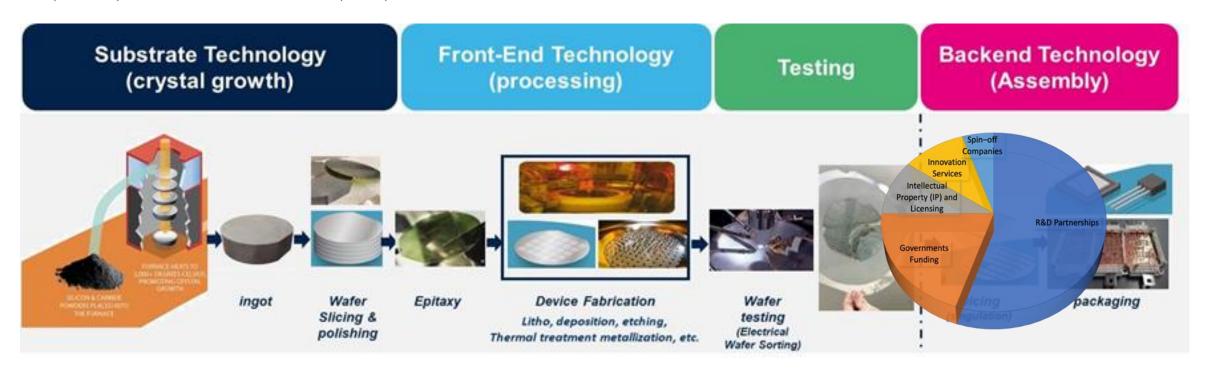
	Euros	
Total cost (EU)	362,609,738	
EU funding	181,304,870	
National funding	181,196,617	

WBG Pilot Line

Pilot line on advanced semiconductor devices based on Wide Bandgap materials:

It will focus on two key outcomes:

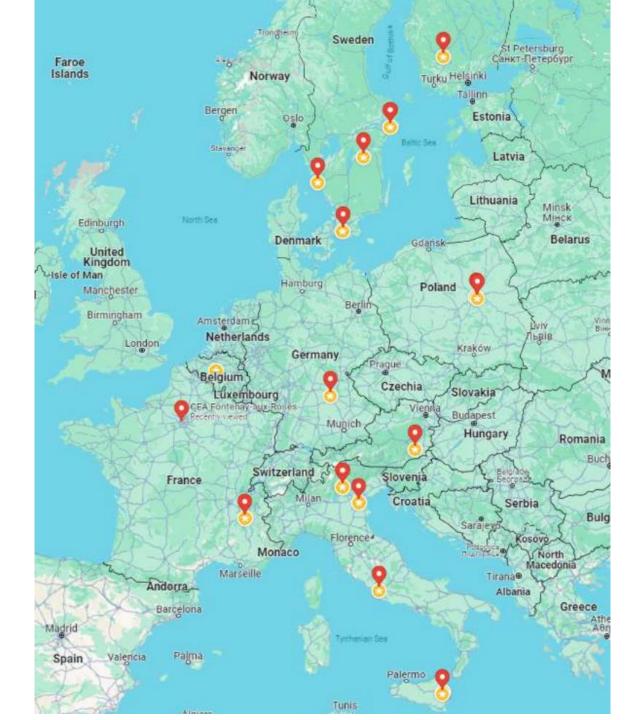
- (i) to extend the maturity level and the impact of SiC and GaN technologies; and
- (ii) to *explore less mature WBG and UWBG semiconductors*, such as cubic polytype of SiC (3C–SiC), low–cost polycrystalline SiC, lattice–matched InAlN or InAlGaN for RF heterostructures, bulk gallium nitride or gallium oxide (Ga₂O₃) or aluminium nitride (AlN).



General idea, vision and topical coverage of the WBG Pilot Line

Participating organizations 14 Partners 7 Countries

CNR
FBK
IU.NET
CHIPS.IT
KTH
LIU
ULUND
Chalmers
Łukasiewicz - IMiF
IHPP PAS
TAU
SAL Austria
CEA LETI
Fraunhofer-IISB









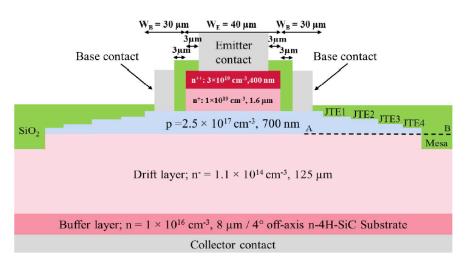
- Electrum Laboratory 1300 m²
- ISO 9001 certified / controlled processes and calibrated characterization tools
- 100 200 mm wafers
- Silicon Technology
- Silicon IC
- Silicon Microsystems
- Compound Semiconductors
- SiC Electronics, 100 mm
- InP Opto / electronics
- GaAs Opto / electronics





KTH Contribution to the WBG Pilot Line: High Voltage SiC BJTs and IGBTs (>3.3 kV)

Mikael Östling, Per-Erik Hellström and Mattias Ekström



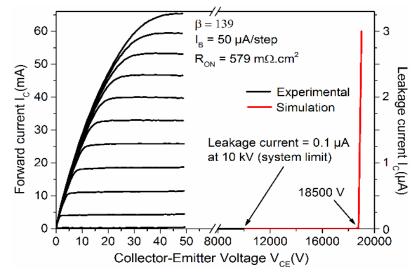


Fig. 1. Schematic cross-sectional view of the fabricated 4H-SiC BJT.

A. Salemi, H. Elahipanah, K. Jacobs, C. -M. Zetterling and M. Östling, "15 kV-Class Implantation-Free 4H-SiC BJTs With Record High Current Gain," in IEEE Electron Device Letters, vol. 39, no. 1, pp. 63-66, Jan. 2018, doi: 10.1109/LED.2017.2774139.

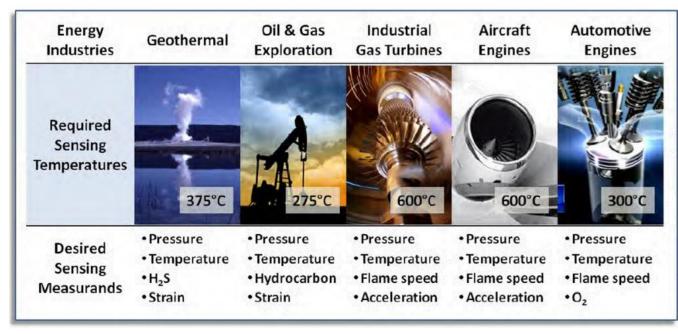
- The pilot line will initially deliver devices based on the the available high current gain (β >130) SiC BJT technology that has been demonstrated to sustain up to 15 kV of collector-emitter voltage.
- The pilot line will initially offer BJT devices for 3-5 kV (TRL level 5) on 150 mm SiC wafers.
- Technology development will bring 15 kV devices, currently at TRL 4 to TRL 5-6.
- In house available innovative, basal plane dislocation-free, 150 mm SiC substrates from KISAB (https://kisabsemi.com)
- The pilot line will also develop IGBT devices on KISABs p-type SiC substrates to be available to the pilot line after the qualification of the BJT devices.



High-Temperature SiC Circuits

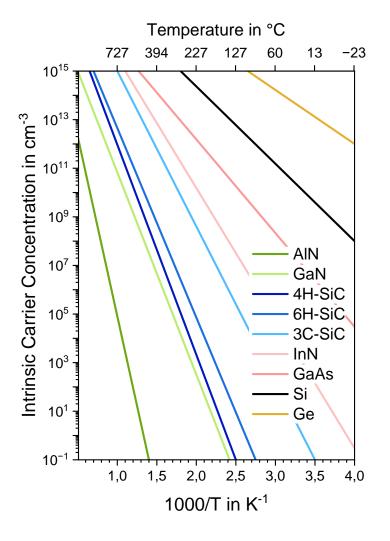


Operation > 500°C



Harsh Environment Sensor Cluster, University of California, San Diego







Summary



- WBG technology will be essential for the sustainable future when it comes to energy efficiency
- A long-term fabrication capacity increase is needed in Europe and globally and new facilities have been established successfully
- SiC market is currently down Dependent on automotive sales but forecast is still very strong
- Power efficiency for data centers increasingly important
- WBG technology still needs materials development in the substrate/epi module







This project has received funding from the European Union's Horizon Europe research and innovation programme under GA N° 101092562

www.icos-semiconductors.eu